

AUTOMOTIVE GRADE

AUIRFR8401 AUIRFU8401

HEXFET® Power MOSFET

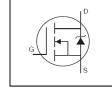
S

Source

Features

Description

- Advanced Process Technology
- New Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *



$V_{ extsf{DSS}}$		40V
R _{DS(on)}	typ.	$3.2 \mathrm{m}\Omega$
	max.	4.25m $Ω$
D (Silicon Lin	nited)	100A①
D (Package L		100A

D I-Pak IRFU8401

D

Drain

G

Gate

Specifically designed for Automotive applications, this HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other applications.	D Frank	Izak
Applications • Electric Power Steering (EPS)	D-Pak AUIRFR8401	AUIF

•	Electric Power Steering (

- **Battery Switch**
- Start/Stop Micro Hybrid
- Heavy Loads
- DC-DC Converter

Daga nart number	Dookogo Typo	Standard Pack		Orderable Port Number
Base part number	Package Type	Form	Quantity	Orderable Part Number
AUIRFU8401	I-Pak	Tube	75	AUIRFU8401
ALUDED0404	D. Dok	Tube	75	AUIRFR8401
AUIRFR8401	D-Pak	Tape and Reel Left	3000	AUIRFR8401TRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	100①	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	71	╗,
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	100	A
I _{DM}	Pulsed Drain Current ②	400	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	79	W
	Linear Derating Factor	0.53	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
TJ	Operating Junction and	-55 to + 175	
T_{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Avalanche Characteristics

/ traiailoilo ollaia	0101101100		
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) 3	67	m l
E _{AS} (tested)	Single Pulse Avalanche Energy (Tested Limited) ®	94	mJ
I _{AR}	Avalanche Current ②	See Fig. 14, 15, 24a, 24b	Α
E _{AR}	Repetitive Avalanche Energy ②		mJ

Thermal Resistance

	~			
Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case		1.9	
$R_{ heta JA}$	Junction-to-Ambient (PCB Mount) ®		50	°C/W
$R_{ heta JA}$	Junction-to-Ambient		110	

HEXFET® is a registered trademark of Infineon.

2016-1-28

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.035		V/°C	Reference to 25°C, I _D = 1.0mA ③
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.2	4.25	mΩ	V _{GS} = 10V, I _D = 60A ⑤
$V_{GS(th)}$	Gate Threshold Voltage	2.2		3.9	V	$V_{DS} = V_{GS}$, $I_D = 50\mu A$
	Drain to Source Leekage Current			1.0	μA	$V_{DS} = 40V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source Leakage Current			150	μΑ	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	n ^	$V_{GS} = 20V$
I _{GSS}	Gate-to-Source Reverse Leakage			-100	nA	$V_{GS} = -20V$
R_G	Internal Gate Resistance		2.0		Ω	

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	-					•
gfs	Forward Trans conductance	198			S	$V_{DS} = 10V, I_{D} = 60A$
Q_g	Total Gate Charge		42	63		$I_D = 60A$
Q_{gs}	Gate-to-Source Charge		12		nC	V _{DS} = 20V
Q_{gd}	Gate-to-Drain Charge		14		110	V _{GS} = 10V ^⑤
Q _{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})		28			
t _{d(on)}	Turn-On Delay Time		7.9			V _{DD} = 20V
t _r	Rise Time		34		20	$I_D = 30A$
$t_{d(off)}$	Turn-Off Delay Time		25		ns	$R_G = 2.7\Omega$
t _f	Fall Time		24			V _{GS} = 10V ^⑤
C _{iss}	Input Capacitance		2200			V _{GS} = 0V
C_{oss}	Output Capacitance		340			V _{DS} = 25V
C_{rss}	Reverse Transfer Capacitance		205		pF	f = 1.0MHz, See Fig. 5
C _{oss eff.} (ER)	Effective Output Capacitance (Energy Related)		410			V_{GS} = 0V, V_{DS} = 0V to 32V ⑦
C _{oss eff.} (TR)	Effective Output Capacitance (Time Related)		495			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V $

Diode Characteristics

						1
	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			100①		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			400	Α	integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 60A, V_{GS} = 0V$ (§
dv/dt	Peak Diode Recovery dv/dt⊕		3.2		V/ns	
t _{rr}	Reverse Recovery Time		28		no	$T_J = 25^{\circ}C$ $V_R = 34V$,
			29		ns	$V_R = 34V$, $V_R = 34V$, $V_R = 34V$, $V_R = 34V$,
Q_{rr}	Reverse Recovery Charge		28		nC	$IJ = 25 C$ di/dt = $100 \Delta / us $ \odot
			31		110	T _J = 125°C
I _{RRM}	Reverse Recovery Current		1.6		Α	T _J = 25°C

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 100A by source bonding technology. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ② Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ③ Limited by T_{Jmax} starting $T_J = 25$ °C, L = 0.037mH, $R_G = 50\Omega$, $I_{AS} = 60$ A, $V_{GS} = 10$ V.
- ⑤ Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- \odot C_{oss eff.} (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- © C_{oss eff}. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- \mathfrak{G} R_θ is measured at T_J approximately 90°C.
- \odot This value determined from sample failure population, starting T_J = 25°C, L=0.037mH, R_G = 25Ω, I_{AS} = 60A, V_{GS} =10V



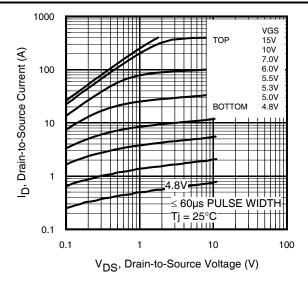


Fig. 1 Typical Output Characteristics

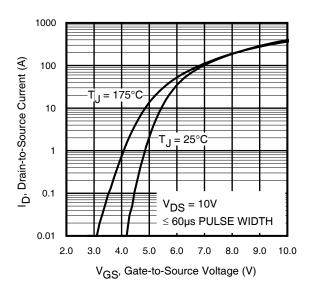


Fig. 3 Typical Transfer Characteristics

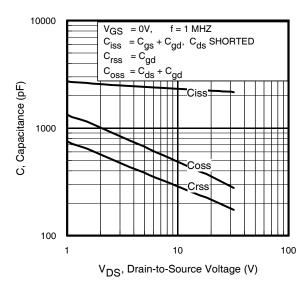


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

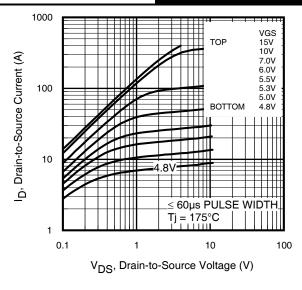


Fig. 2 Typical Output Characteristics

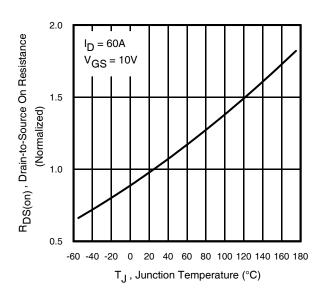


Fig. 4 Normalized On-Resistance vs. Temperature

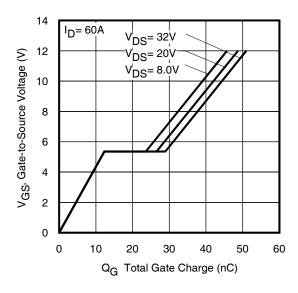


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



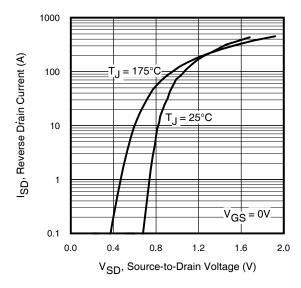


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

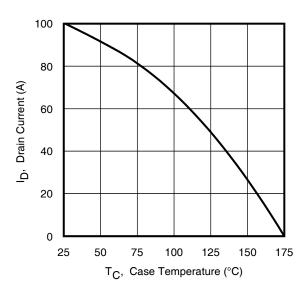


Fig. 9 Maximum Drain Current vs. Case Temperature

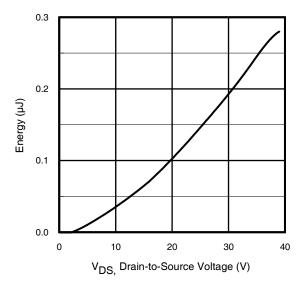


Fig. 11 Typical Coss Stored Energy

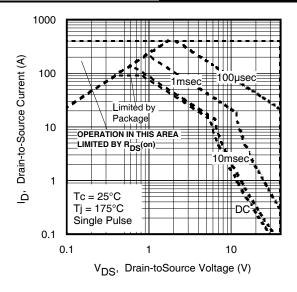


Fig 8. Maximum Safe Operating Area

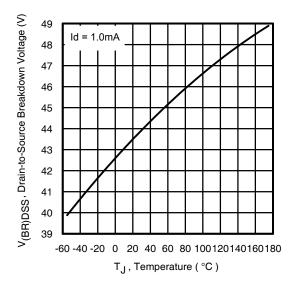


Fig 10. Drain-to-Source Breakdown Voltage

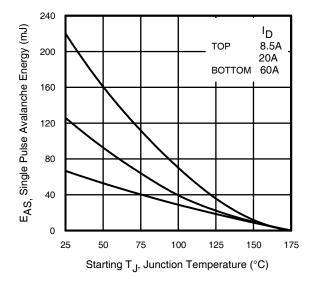


Fig 12. Maximum Avalanche Energy vs. Drain Current



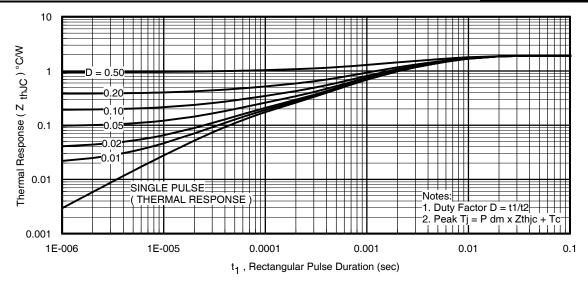


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

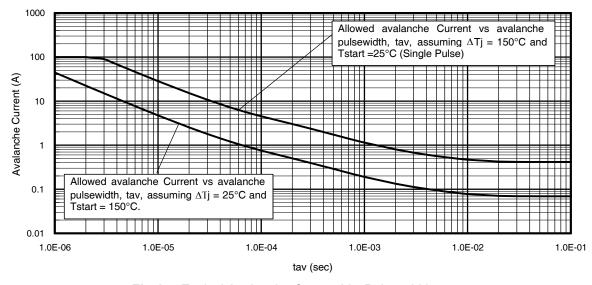


Fig 14. Typical Avalanche Current Vs. Pulse width

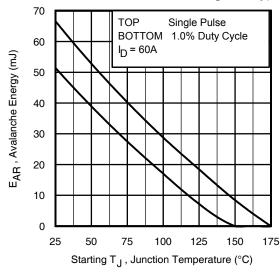


Fig 15. Maximum Avalanche Energy Vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in
- excess of T_{jmax}. This is validated for every part type.

 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 13, 14).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ (} 1.3 \cdot \text{BV} \cdot \text{I}_{av} \text{)} = \Delta \text{T} / \text{Z}_{thJC} \\ I_{av} &= 2\Delta \text{T} / \text{ [} 1.3 \cdot \text{BV} \cdot \text{Z}_{th} \text{]} \\ E_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$

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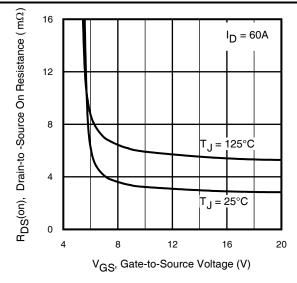


Fig 16. On-Resistance vs. Gate Voltage

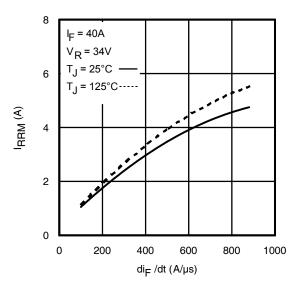


Fig. 18 - Typical Recovery Current vs. dif/dt

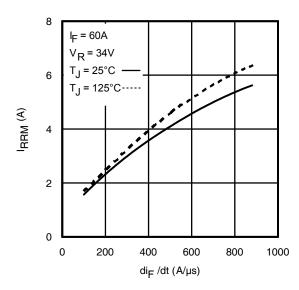


Fig. 20 - Typical Recovery Current vs. dif/dt

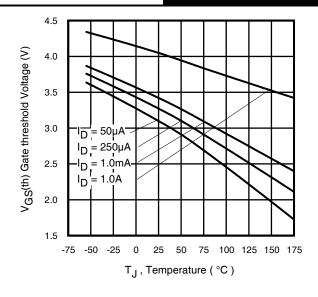


Fig. 17 - Threshold Voltage vs. Temperature

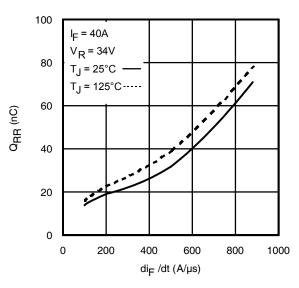


Fig. 19 - Typical Stored Charge vs. dif/dt

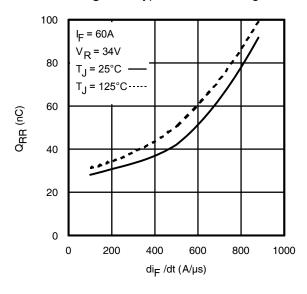


Fig. 21 - Typical Stored Charge vs. dif/dt



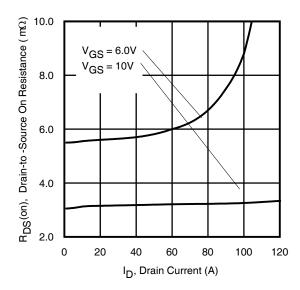


Fig 22. Typical On-Resistance vs. Drain Current

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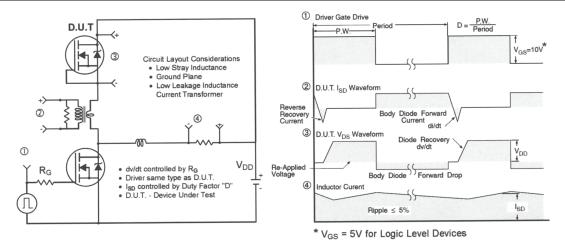


Fig 23. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

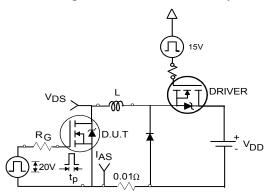


Fig 24a. Unclamped Inductive Test Circuit

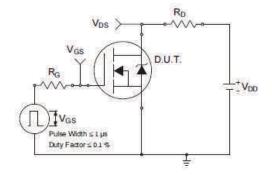


Fig 25a. Switching Time Test Circuit

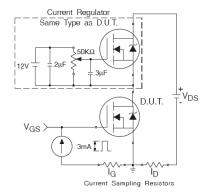


Fig 26a. Gate Charge Test Circuit

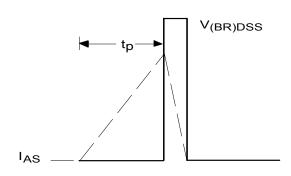


Fig 24b. Unclamped Inductive Waveforms

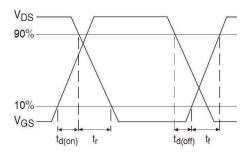


Fig 25b. Switching Time Waveforms

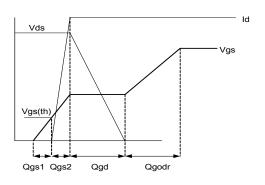


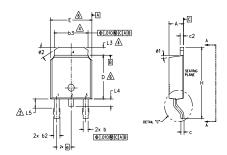
Fig 26b. Gate Charge Waveform

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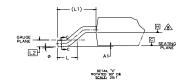
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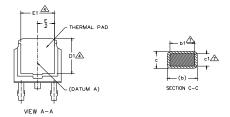


D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- Limension D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION 61 & c1 APPLIED TO BASE METAL ONLY.
- ♠ DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S Y M		DIMEN	SIONS		Ŋ
B	MILLIM	ETERS	INC	HES	O T E S
L	MIN.	MAX.	MIN.	MAX.	S
Α	2.18	2.39	.086	.094	
A1	-	0.13	-	.005	
b	0.64	0.89	.025	.035	
ь1	0.65	0.79	.025	.031	7
b2	0.76	1.14	.030	.045	
b3	4.95	5.46	.195	.215	4
С	0.46	0.61	.018	.024	
с1	0.41	0.56	.016	.022	7
c2	0.46	0.89	.018	.035	
D	5.97	6.22	.235	.245	6
D1	5.21	-	.205	-	4
Ε	6.35	6.73	.250	.265	6
E1	4.32	-	.170	-	4
е	2.29	BSC	.090	BSC	
Н	9.40	10.41	.370	.410	
L	1.40	1.78	.055	.070	
L1	2.74	BSC	.108	REF.	
L2	0.51	BSC	.020	BSC	
L3	0.89	1.27	.035	.050	4
L4	-	1.02	-	.040	
L5	1.14	1.52	.045	.060	3
ø	0,	10*	0,	10°	
ø1	0,	15*	0,	15*	
ø2	25*	35°	25*	35°	

LEAD ASSIGNMENTS

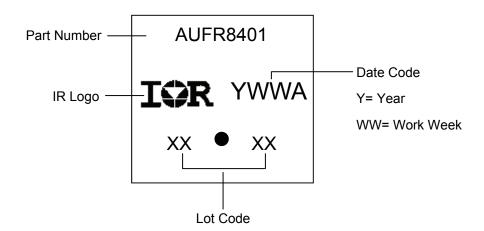
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE 4.- DRAIN

IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER
- 4.- COLLECTOR

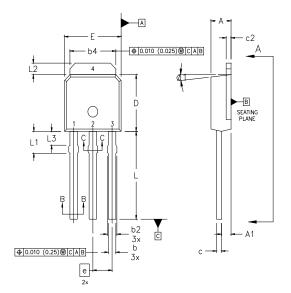
D-Pak (TO-252AA) Part Marking Information

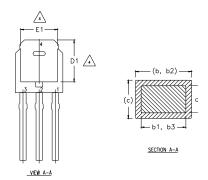


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



I-Pak (TO-251AA) Package Outline (Dimensions are shown in millimeters (inches)





NOTES:

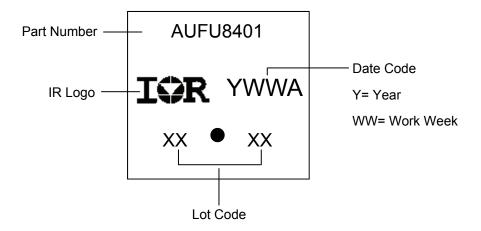
- 1 DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- 2 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3 DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED 0.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 4 THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
 - LEAD DIMENSION UNCONTROLLED IN L3.
- 6 DIMENSION 61, 63 APPLY TO BASE METAL ONLY.
 - OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA.
- 8 CONTROLLING DIMENSION : INCHES.

LEAD ASSIGNMENTS

HEX	Jr E

- 1.- GATE 2.- DRAIN
- 3.- SOURCE 4.- DRAIN
- DIMENSIONS SYMBOL MILLIMETERS INCHES MIN. NOTES 2.18 2.39 0.086 .094 A1 0.89 1.14 0.035 0.045 b 0.64 0.89 0.025 0.035 ь1 0.64 0.79 0.025 0.031 b2 0.76 1.14 0.030 0.045 0.76 1.04 0.030 0.041 5.00 5.46 0.195 0.215 b4 0.46 0.61 0.018 0.024 0.016 0.022 0.41 0.56 c1 c2 .046 0.86 0.018 0.035 D 5.97 6.22 0.235 0.245 D1 5.21 0.205 6.35 6.73 0.250 0.265 E1 4.32 0.170 0.090 BSC е L 8.89 9.60 0.350 0.380 L1 1,91 2.29 0.075 0.090 L2 0.89 1.27 0.035 0.050 L3 1.14 1.52 0.045 0.060 15*

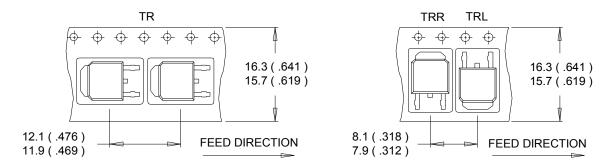
I-Pak (TO-251AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

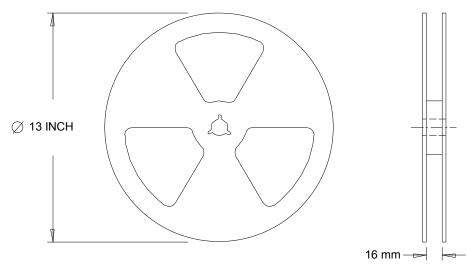


D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

40000			
Qualification Level		Automotive (per AEC-Q101)	
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.	
Moisture Sensitivity Level		D-Pak	MSL1
		I-Pak	
ESD	Machine Model		Class M2 (+/- 200V) [†]
		AEC-Q101-002	
	Human Body Model	Class H1B (+/- 1000V) [†]	
		AEC-Q101-001	
	Charged Device Model	Class C5 (+/- 2000V) [†]	
		AEC-Q101-005	
RoHS Compliant		Yes	

[†] Highest passing voltage.

Revision History

Date	Comments
12/14/2015	 Updated datasheet with corporate template Corrected ordering table on page 1.
1/28/2016	Corrected Qualification table (Human Body model value) on page 12.

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